IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Date

For:

February 11, 2009

In re the Application of

Hideki SATO

Application No.: 10/594,458

Filed: September 26, 2006

METHOD FOR EVALUATING CRYSTAL DEFECTS OF SILICON WAFER

Group Art Unit: 1792

Examiner:

L. VINH

Docket No.: 129546

LARGE ENTITY PETITION FOR 1st - 3rd EXTENSION

OF TIME UNDER 37 C.F.R. §1.136(a) AND TRANSMITTAL OF FEE UNDER 37 C.F.R. §1.17

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Transmitted herewith is a response to the outstanding Official Action in the above-identified patent application. The shortened statutory period having expired December 15, 2008, an extension of time for a period of two months is hereby requested. Attached hereto is our Check No. 215097 in the amount of \$490 in payment for:

	Extension fee for response within first month pursuant to §1.136(a) (\$130.00)
X	Extension fee for response within second month pursuant to §1.136(a) (\$490.00)

Extension fee for response within third or subsequent month pursuant to §1.136(a) (\$1,110.00)

The Commissioner is hereby authorized to charge any additional fee or credit any overpayment associated with this communication to Deposit Account No. 15-0461.

Respectfully submitted,

William P. Berridge Registration No. 30,024

Nicolas A. Brentlinger

Registration/No.26232141NDAF1 66600143 16594458

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Mh A. M

490.00 OP

WPB:NAB/kjl

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OLIFF & BERRIDGE, PLC P.O. Box 320850 Alexandria, Virginia 22320-4850 Telephone: (703) 836-6400

DEPOSIT ACCOUNT USE **AUTHORIZATION** Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461